



**MICROCIRCUIT DATA SHEET**

**CN74F10-X REV 0A0**

Original Creation Date: 12/05/96  
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**TRIPLE 3-INPUT NAND GATE**

**General Description**

This device contains three independent gates, each of which performs the logic NAND function.

**Industry Part Number**

74F10

**NS Part Numbers**

74F10DC

**Prime Die**

M010

**Processing**

(blank)

**Quality Conformance Inspection**

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Subgrp	Description	Temp ( °C)
1	Static tests at	+25
2	Static tests at	+70
3	Static tests at	0
4	Dynamic tests at	+25
5	Dynamic tests at	+70
6	Dynamic tests at	0
7	Functional tests at	+25
8A	Functional tests at	+70
8B	Functional tests at	0
9	Switching tests at	+25
10	Switching tests at	+70
11	Switching tests at	0

**(Absolute Maximum Ratings)**

(Note 1)

Storage Temperature	-65 C to +150 C
Ambient Temperature under Bias	-55 C to +125 C
Junction Temperature under Bias	-55 C to +175 C
Vcc Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0mA
Voltage Applied to Output in HIGH State (with Vcc=0V)	
Standard Output	-0.5V to Vcc
TRI-STATE Output	-0.5V to +5.5V
Current Applied to Output in LOW State (Max)	twice the rated Iol(mA)

Note 1: Absolute Maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

**Recommended Operating Conditions**

Free Air Ambient Temperature Commercial	0 C to +70 C
Supply Voltage Commercial	+4.5V to +5.5V

## Electrical Characteristics

### DC PARAMETER

(The following conditions apply to all the following parameters, unless otherwise specified.)  
DC: VCC 4.5V to 5.5V, Temp range: 0C to +70C

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
VIH	Input HIGH Voltage	Recognized as a HIGH Signal	1	INPUTS	2.0		V	1, 2, 3
VIL	Input LOW Voltage	Recognized as a LOW Signal	1	INPUTS		0.8	V	1, 2, 3
VCD	Input Clamp Diode Voltage	VCC=4.5V, IIN=-18mA	2, 3	INPUTS		-1.2	V	1, 2, 3
VOH	Output HIGH Voltage	VCC=4.5V, IOH=-1.0mA	2, 3	OUTPUTS	2.5		V	1, 2, 3
		VCC=4.75V, IOH=-1.0mA	2, 3	OUTPUTS	2.7		V	1, 2, 3
VOL	Output LOW Voltage	VCC=4.5V, IOL=20mA	2, 3	OUTPUTS		0.5	V	1, 2, 3
IIH	Input HIGH Current	VCC=5.5V, VIN=2.7V	2, 3	INPUTS		5.0	uA	1, 2, 3
IBVI	Input HIGH Current Breakdown Test	VCC=5.5V, VIN=7.0V	2, 3	INPUTS		7.0	uA	1, 2, 3
ICEX	Output HIGH Leakage Current	VCC=5.5V, VOUT = VCC	2, 3	OUTPUTS		100	uA	1, 2, 3
VID	Input Leakage Test	VCC = 0.0V, IID = 1.9uA, All other pins grounded	2, 3	INPUTS	4.75		V	1, 2, 3
IOD	Output Leakage Circuit Current	VCC = 0.0V, VIOD = 150mV, All other pins grounded	2, 3	OUTPUTS		4.75	uA	1, 2, 3
IIL	Input LOW Current	VCC=5.5V, VIN = 0.5V	2, 3	INPUTS		-0.6	mA	1, 2, 3
IOS	Output Short-Circuit Current	VCC=5.5V, VOUT=0V	2, 3	OUTPUTS	-60	-150	mA	1, 2, 3
ICCH	Power Supply Current	VCC=5.5V, VO = HIGH	2, 3	VCC		2.1	mA	1, 2, 3
ICCL	Power Supply Current	VCC=5.5V, VO = LOW	2, 3	VCC		7.7	mA	1, 2, 3

## Electrical Characteristics

### AC PARAMETER

(The following conditions apply to all the following parameters, unless otherwise specified.)  
 AC: CL=50pF, RL=500 OHMS TR=2.5ns, TF=2.5ns SEE AC FIGS. Temp Range: 0C to +70C

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
tpLH	Propagation Delay	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	An/Bn/Cn to $\bar{O}n$	2.4	5.0	ns	9
			2, 3	An/Bn/Cn to $\bar{O}n$	2.4	6.0	ns	10, 11
tpHL	Propagation Delay	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	An/Bn/Cn to $\bar{O}n$	1.5	4.3	ns	9
			2, 3	An/Bn/Cn to $\bar{O}n$	1.5	5.3	ns	10, 11

Note 1: Guaranteed by applying specific input condition and testing VOL & VOH.

Note 2: Screen tested 100% on each device at +75C temperature only, subgroups A2 & A10.

Note 3: Sample tested (Method 5005, Table 1) on each MFG. lot at +75C temperature only, subgroups A2 & A10.